

REVISIONS

LTR	DESCRIPTION	DATE	APPROVED

REV																			
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REV STATUS OF PAGES	REV																		
	SHEET	1	2	3	4	5	6	7	8	9	10	11							

<p><b>Defense Electronics Supply Center Dayton, Ohio</b></p> <p><b>Original date of drawing:</b> 23 February 1987</p> <p>AMSC N/A</p>	PREPARED BY DAVID W. QUEENAN		<p align="center"><b>MILITARY DRAWING</b></p> <p align="center"><b>This drawing is available for use by all Departments and Agencies of the Department of Defense</b></p>															
	CHECKED BY D A Di Cenzo																	
	APPROVED BY N A Hauck		TITLE: MICROCIRCUIT, DIGITAL, BIPOLAR, BCD COUNTER, MONOLITHIC SILICON															
	SIZE <b>A</b>	CODE IDENT. NO. <b>14933</b>	DWG NO. <b>5962-86727</b>															
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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table and logic diagram. The truth table and logic diagram shall be as specified on figure 2.

3.2.3 Logic diagram. Logic diagram shall be specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

<b>MILITARY DRAWING</b> <b>DEFENSE ELECTRONICS SUPPLY CENTER</b> <b>DAYTON, OHIO 45444</b>	SIZE <b>A</b>	CODE IDENT. NO. <b>14933</b>	DWG NO. <b>5962-86727</b>
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TABLE I. Electrical performance characteristics.

Test	Symbol	Condition 1/ -55°C ≤ T <sub>C</sub> ≤ +125°C (unless otherwise specified)	Group A subgroups	Limits		Unit	
				Min	Max		
High level output voltage	V <sub>OH</sub>	V <sub>CC</sub> = 4.5 V V <sub>IN</sub> = 0.8 V or 2.0 V I <sub>OH</sub> = -1.0 mA	1, 2, 3	2.5		V	
Low level output voltage	V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V V <sub>IN</sub> = 2.0 V or 0.8 V I <sub>OL</sub> = 20.0 mA	1, 2, 3		0.5		
Input clamp voltage	V <sub>IC</sub>	V <sub>CC</sub> = 4.5 V I <sub>IN</sub> = -18.0 mA	1, 2, 3		-1.2	V	
Low level input current	I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 0.5 V	P; $\overline{MR}$ ; CEP	1, 2, 3		-2.0	mA
			CET	1, 2, 3		-3.0	mA
			$\overline{PE}$			-4.0	
			CP			-5.0	
High level input current	I <sub>IH</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 2.7 V	P; $\overline{MR}$ ; CEP	1, 2, 3		50	uA
			CET			75	uA
			$\overline{PE}$			100	uA
			CP			125	uA
		V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 5.5 V		1.0	mA		
Short circuit output current	I <sub>OS</sub>	V <sub>CC</sub> = 5.5 V V <sub>OUT</sub> = 0 V	1, 2, 3	-40	-100	mA	
Supply current	I <sub>CC</sub>	V <sub>CC</sub> = 5.5 V Measured with $\overline{MR}$ = 0 V, all other inputs high and all outputs open	1, 2, 3		127	mA	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Condition 1/ -55°C ≤ T <sub>C</sub> ≤ +125°C (unless otherwise specified)		Group A subgroups	Limits		Unit
					Min	Max	
Propagation delay from clock to Q output	t <sub>PLH1</sub>	C <sub>L</sub> = 15 pF R <sub>L</sub> = 280Ω	T <sub>A</sub> = 25°C 2/	9		9	ns
			3/	9, 10, 11		11	
	t <sub>PHL1</sub>		T <sub>A</sub> = 25°C 2/	9		13	ns
			3/	9, 10, 11		15	
Propagation delay from clock to T <sub>C</sub>	t <sub>PLH2</sub>	T <sub>A</sub> = 25°C 2/	9		18	ns	
		3/	9, 10, 11		20		
	t <sub>PHL2</sub>	T <sub>A</sub> = 25°C 2/	9		12	ns	
		3/	9, 10, 11		14		
Propagation delay from CET to T <sub>C</sub>	t <sub>PLH3</sub>	T <sub>A</sub> = 25°C 2/	9		10	ns	
		3/	9, 10, 11		12		
	t <sub>PHL3</sub>	T <sub>A</sub> = 25°C 2/	9		10	ns	
		3/	9, 10, 11		11		
Propagation delay from MR to Q	t <sub>PHL4</sub>	T <sub>A</sub> = 25°C 2/	9		20	ns	
		3/	9, 10, 11		22		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Condition 1/ -55°C ≤ T <sub>C</sub> ≤ +125°C (unless otherwise specified)		Group A subgroups	Limits		Unit
					Min	Max	
Recovery time for $\overline{MR}$ (inactive)	t <sub>rec</sub>		T <sub>A</sub> = 25°C <u>2/</u>	9	6		ns
			<u>3/</u>	9, 10, 11	8		
Master reset ( $\overline{MR}$ ) pulse width	t <sub>pw1</sub>		T <sub>A</sub> = 25°C <u>2/</u>	9	13		ns
			<u>3/</u>	9, 10, 11	17		
Clock pulse width	t <sub>pw2</sub>	<u>2/</u>	T <sub>A</sub> = 25°C HIGH	9	6		ns
			LOW	9, 10, 11	10		
		<u>3/</u>	T <sub>A</sub> = 25°C HIGH	9	8		ns
			LOW	9, 10, 11	13		
Data setup time	t <sub>s1</sub>		T <sub>A</sub> = 25°C <u>2/</u>	9	8		ns
			<u>3/</u>	9, 10, 11	10		
Data hold time	t <sub>h1</sub>		T <sub>A</sub> = 25°C <u>2/</u>	9	0		ns
			<u>3/</u>	9, 10, 11	0		
PE setup time	t <sub>s2</sub>		T <sub>A</sub> = 25°C <u>2/</u>	9	16		ns
			<u>3/</u>	9, 10, 11	21		
PE hold time	t <sub>h2</sub>		T <sub>A</sub> = 25°C <u>2/</u>	9	0		ns
			<u>3/</u>	9, 10, 11	0		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Condition 1/ -55°C ≤ T <sub>C</sub> ≤ +125°C (unless otherwise specified)	Group A subgroups	Limits		Unit
				Min	Max	
CEP or CET setup time	t <sub>s3</sub>		T <sub>A</sub> = 25°C 2/	9	12	ns
			3/	9, 10, 11	16	
CEP or CET hold time	t <sub>h3</sub>		T <sub>A</sub> = 25°C 2/	9	0	ns
			3/	9, 10, 11	0	

1/ Not more than one output should be shorted at a time. Duration of the short circuit condition should not exceed one second.

2/ V<sub>CC</sub> = 5.0 V.

3/ V<sub>CC</sub> = 4.5 V to 5.5 V.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

#### 4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test (method 1015 of MIL-STD-883).

(1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2) T<sub>A</sub> = 125°C, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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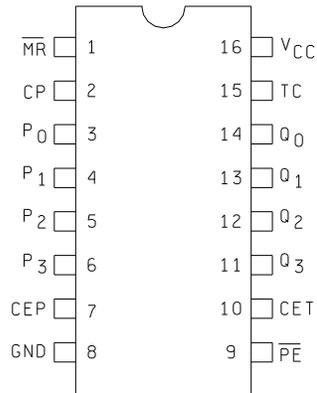


FIGURE 1. Terminal connections.

Inputs									Outputs			
CP	$\overline{MR}$	$\overline{PE}$	CEP	CET	P <sub>0</sub>	P <sub>1</sub>	P <sub>2</sub>	P <sub>3</sub>	Q <sub>0</sub>	Q <sub>1</sub>	Q <sub>2</sub>	Q <sub>3</sub>
X	L	X	X	X	X	X	X	X	L	L	L	L
↑	H	L	X	X	D <sub>0</sub>	D <sub>1</sub>	D <sub>2</sub>	D <sub>3</sub>	D <sub>0</sub>	D <sub>1</sub>	D <sub>2</sub>	D <sub>3</sub>
↑	H	H	L	L	X	X	X	X	NC	NC	NC	NC
↑	H	H	L	H	X	X	X	X	NC	NC	NC	NC
↑	H	H	H	L	X	X	X	X	NC	NC	NC	NC
↑	H	H	H	H	X	X	X	X	cOUNT			

H = High level  
 L = Low level  
 X = Don't care

NC = No change  
 D<sub>i</sub> may be either high or low  
 ↑ Low-to-high Transition

FIGURE 2. Truth table.

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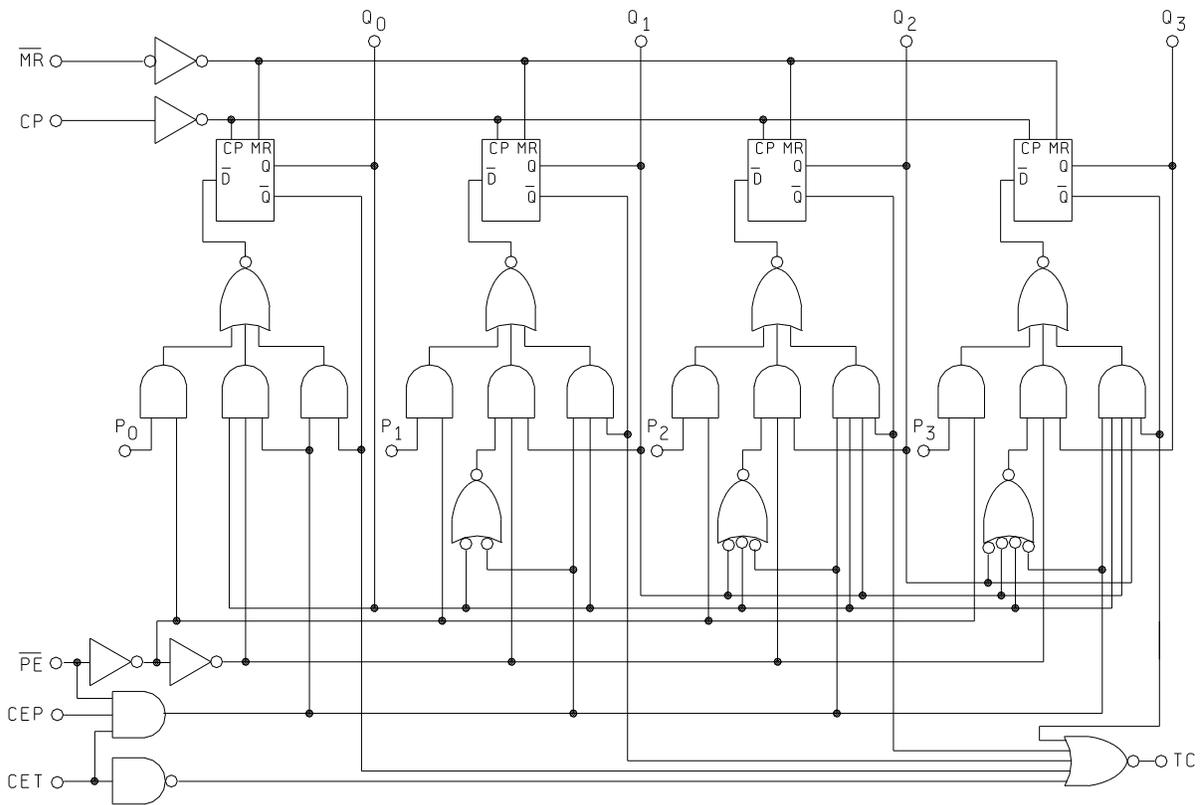


FIGURE 3. Logic diagram.

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4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 7 and 8 shall verify the truth table.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
  - (1) Test condition A, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
  - (2)  $T_A = +125^\circ\text{C}$ , minimum.
  - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups ( per method 5005, table I )
Interim electrical parameters (method 5004)	- - -
Final electrical test parameters (method 5004)	1*,2,3,7,8,9,10,11
Group A test requirements (method 5005)	1,2,3,7,8,9,10**, 11**
Group C and D end-point electrical parameters (method 5005)	1,2,3

\* PDA applies to subgroup 1.

\*\* Subgroup 10 and 11, if not tested, shall be guaranteed to the limits specified in table I.

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5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <sup>1/</sup>
5962-8672701EX	34335	93S16/BEA
5962-8672701FX	34335	93S16/BFA

<sup>1/</sup> Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

34335

Vendor name and address

Advanced Micro Devices, Inc.  
901 Thompson Place  
P.O. Box 3453  
Sunnyvale, CA 94088

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